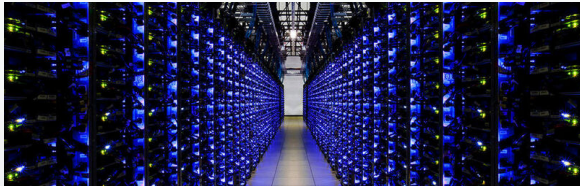


Technology Developments & Equipment Requirements for Scaling Up Photonics Production

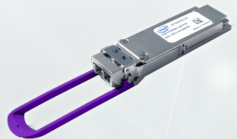
Torsten Vahrenkamp & Stefano Concezzi
Presentation generated by Moritz Seyfried

Photonics – It is just everywhere

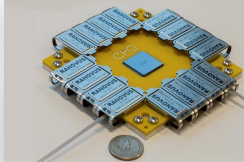
Telecom/Datacom



Datacenter, [Credit: google/datacenter]



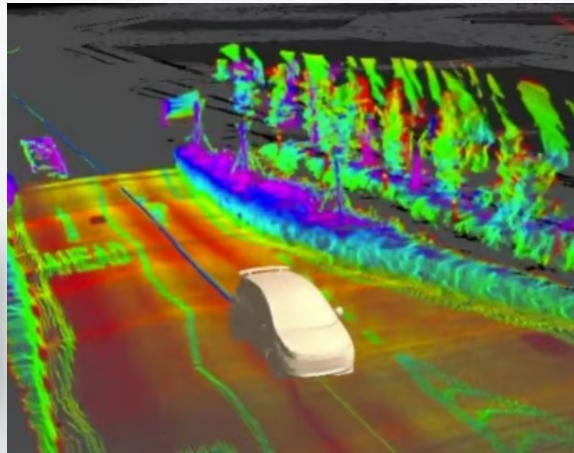
400G Transceiver module
[Credit: Intel]



CPO vision
[Credit: Ranovus]

Optical backbone of data centers and telecommunication networks. Pluggable or CPO.

LiDAR Development



Solid-state-based LiDAR systems, e.g. Intel/Mobileye LiDAR system.

Bio-Sensing



Optical sensing of bio-markers for constant medical monitoring.
[Rockley Photonics]

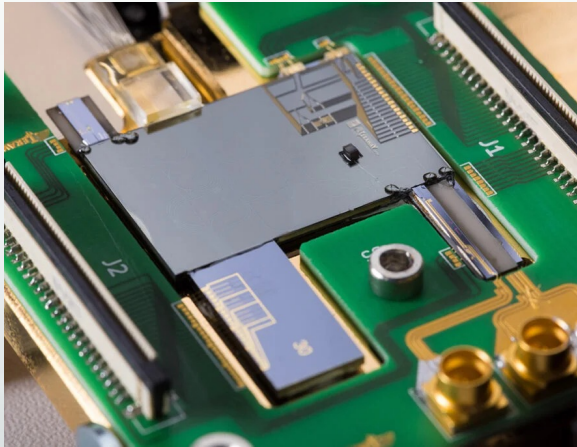
Quantum Technology



Generation of entangled photons for quantum key distribution.
[Quantum Optics Jena]

PICs inside

Telecom/Datacom



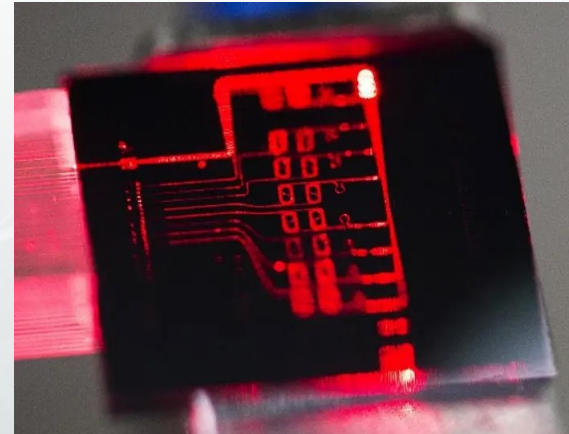
PIC-based approach from PHIX/Teraway for high-speed transceiver module.

LiDAR Development



Solid-state-based LiDAR systems such as e.g. Intel/Mobileye LiDAR system. [Mobileye]

Bio-Sensing



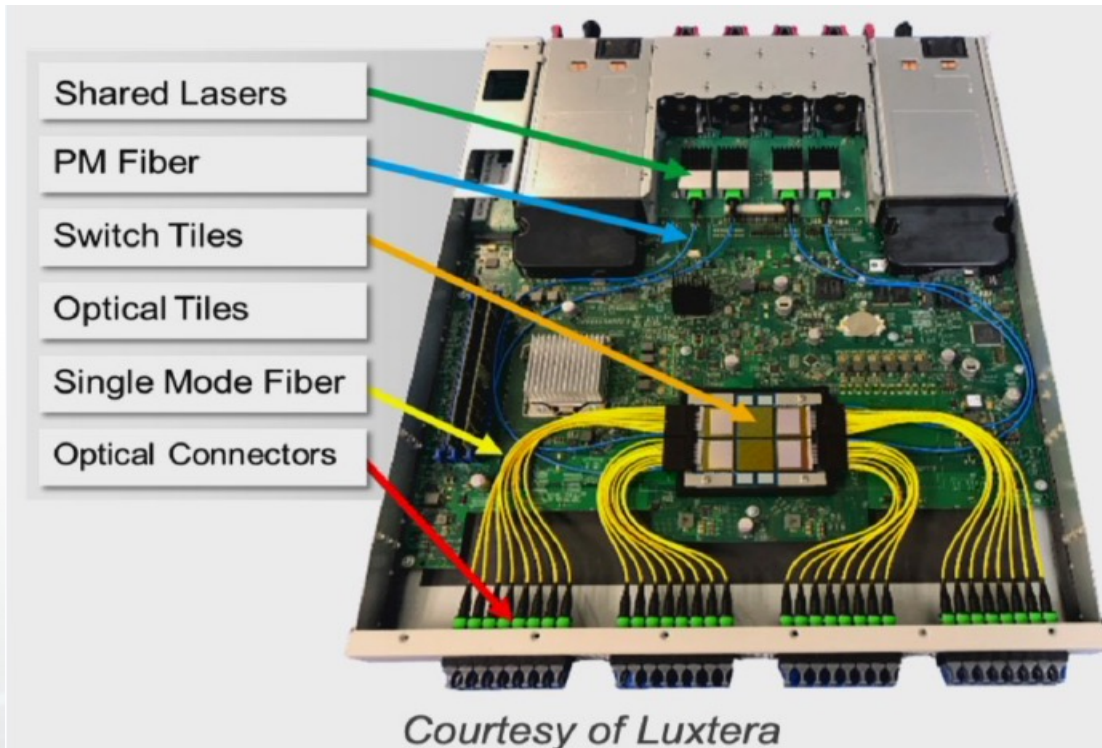
8 MZI building blocks showing waveguides outlining the sensing area to be functionalized. [LioniX]

Quantum Technology



PIC-based approach for building a large-scale quantum computer. [PsiQuantum]

PIC product assembly



- Known good photonic integrated circuits (PICs)
- Need for electro-optical (wafer-level) testing

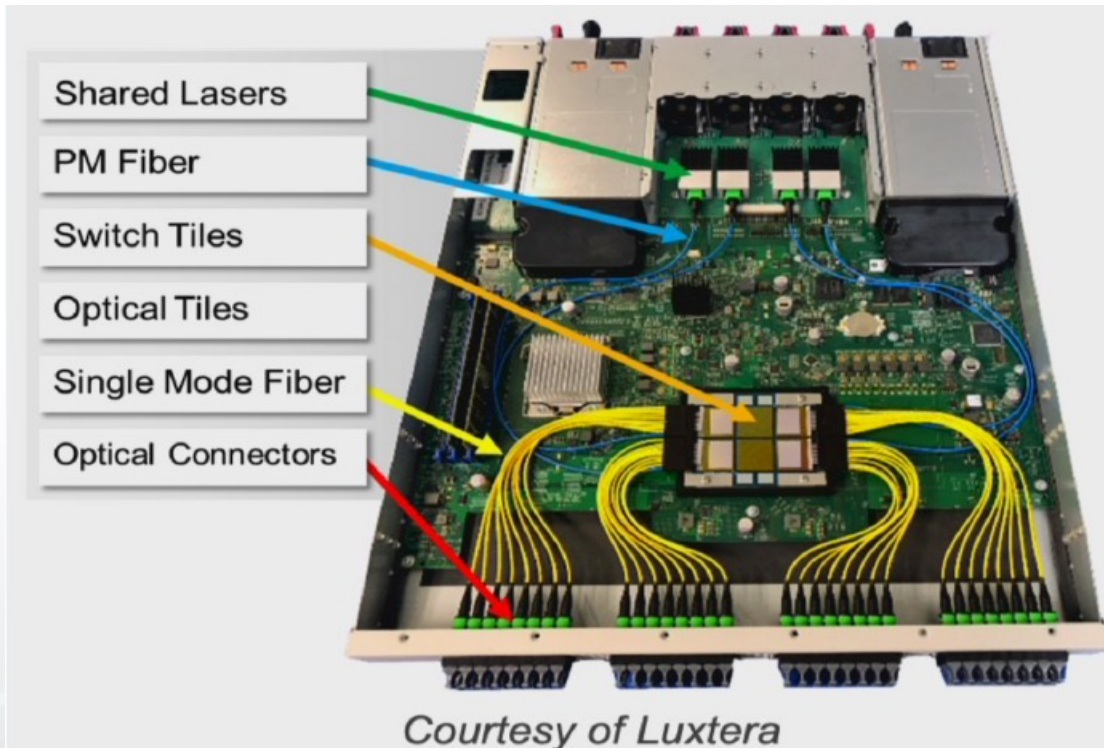
- Integration of laser source
- Need for high-precision die bonding

- Fiber array assembly and alignment
- Need for fiber interconnect

- Reliable machine for volume production
- Need for line systems and machine learning

PIC product assembly

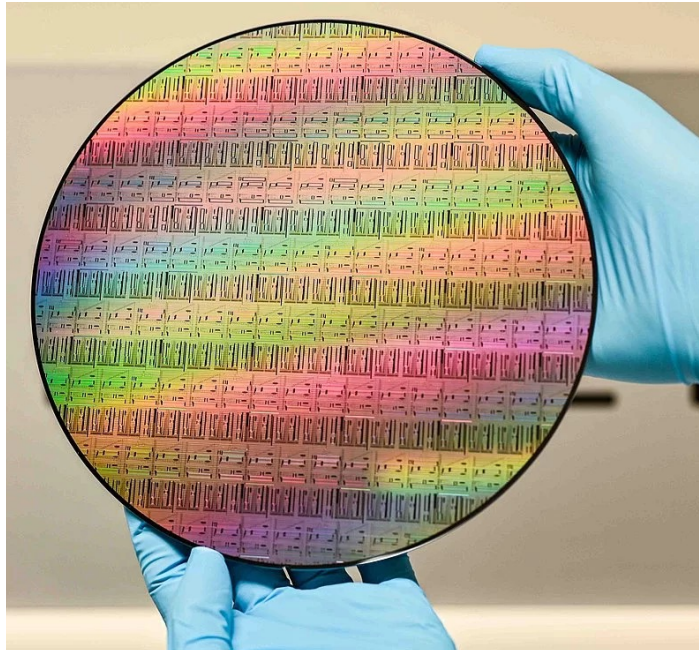
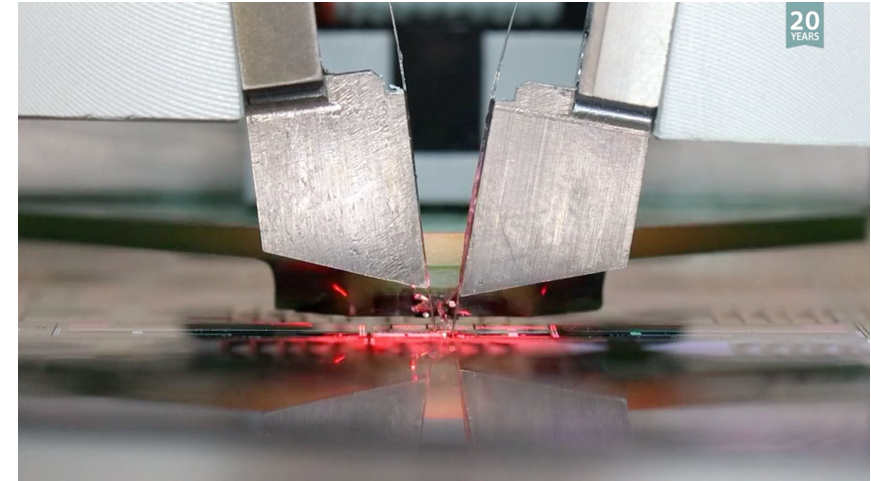
- Known good photonic integrated circuits (PICs)
- Need for electro-optical (wafer-level) testing



- Integration of laser source
- Need for high-precision die bonding
- Fiber array assembly and alignment
- Need for fiber interconnect
- Machine for assembly
- Need for line systems and machine learning

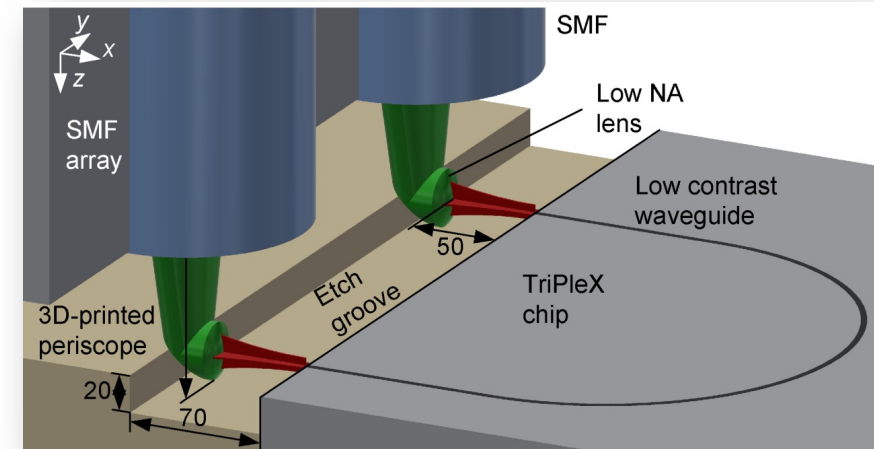
Electro-optical wafer-level testing

Grating coupling



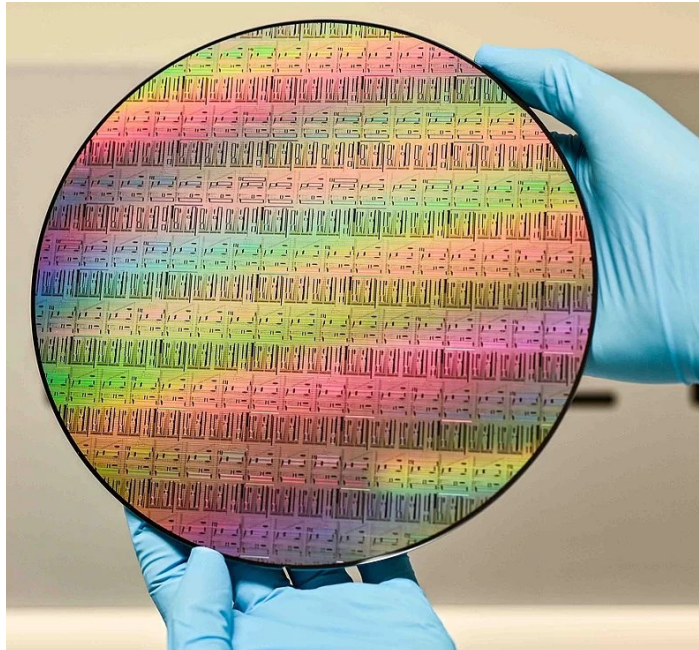
Electro-optical wafer-level tester for verification of PIC functionality

Edge coupling

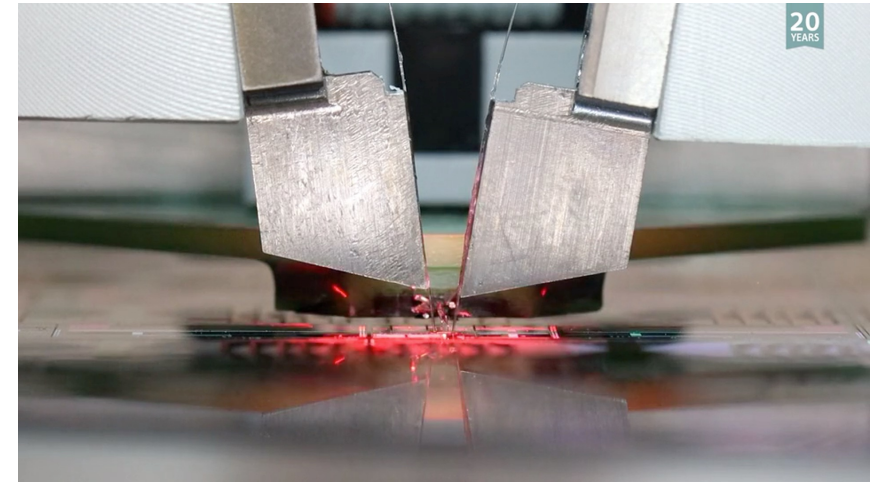


Electro-optical wafer-level testing

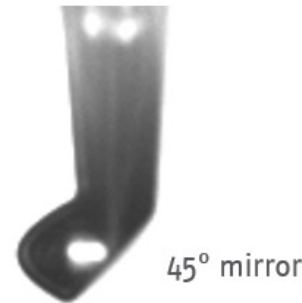
Grating coupling



Electro-optical wafer-level tester for verification of PIC functionality



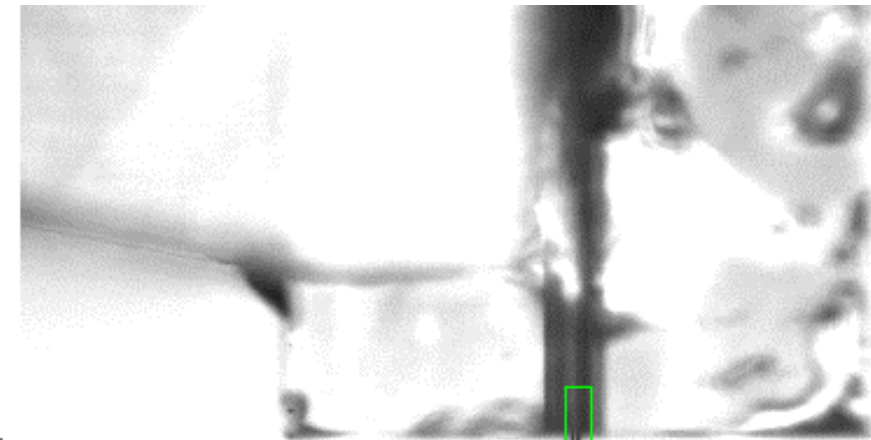
Edge coupling



lens surface

45° mirror

50 μm



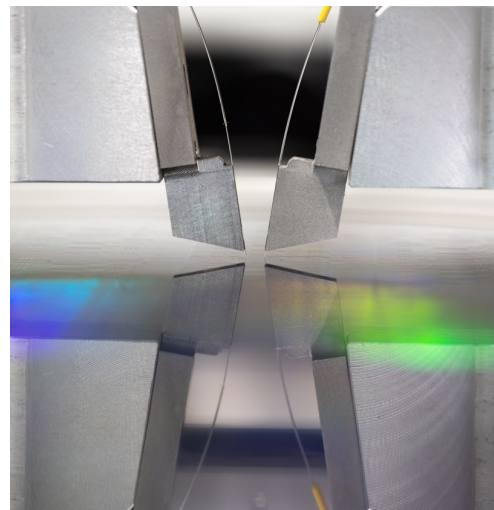
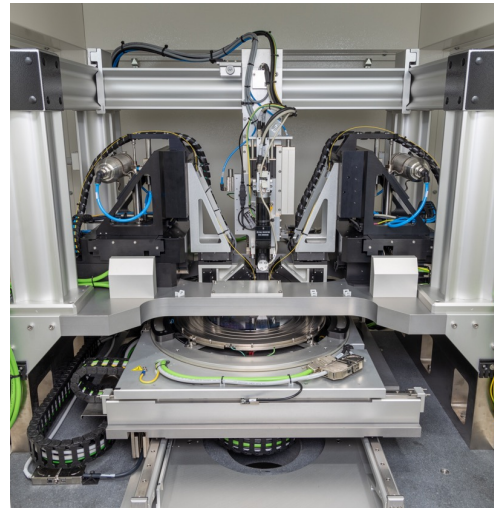
3D printed lens periscope

Electro-optical wafer-level testing



Electro-optical wafer-level tester for verification of PIC functionality

Wafer table

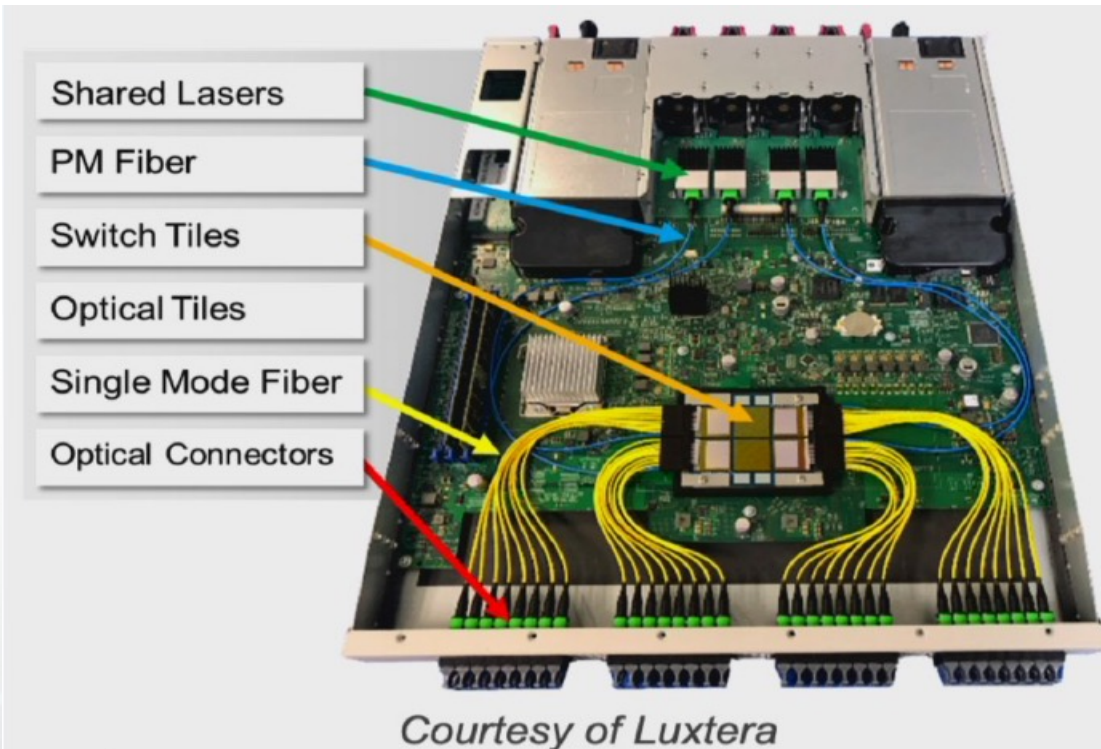


Optical alignment

Next-generation wafer-level tester:

- Throughput requirements
- Interaction with available tester
- RF requirements
- Measurement equipment
- Data handling
-

PIC product assembly



- Known good photonic integrated circuits (PICs)
- Need for electro-optical (wafer level) testing

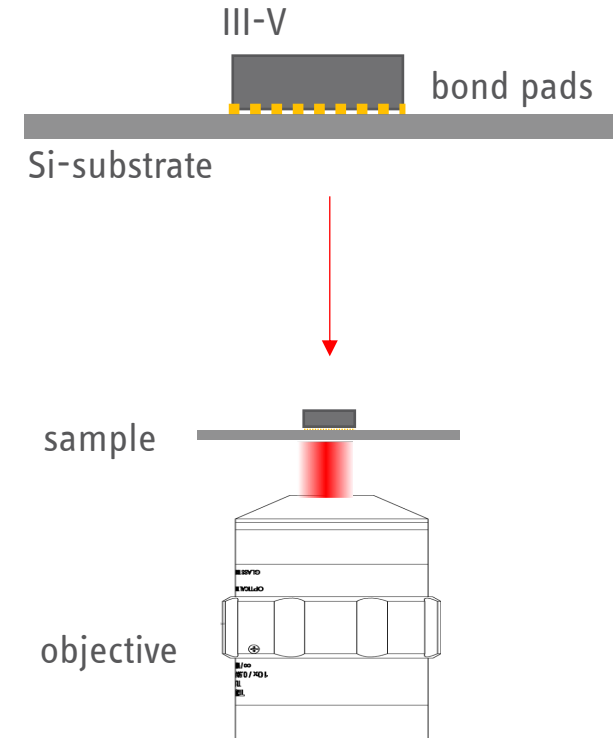
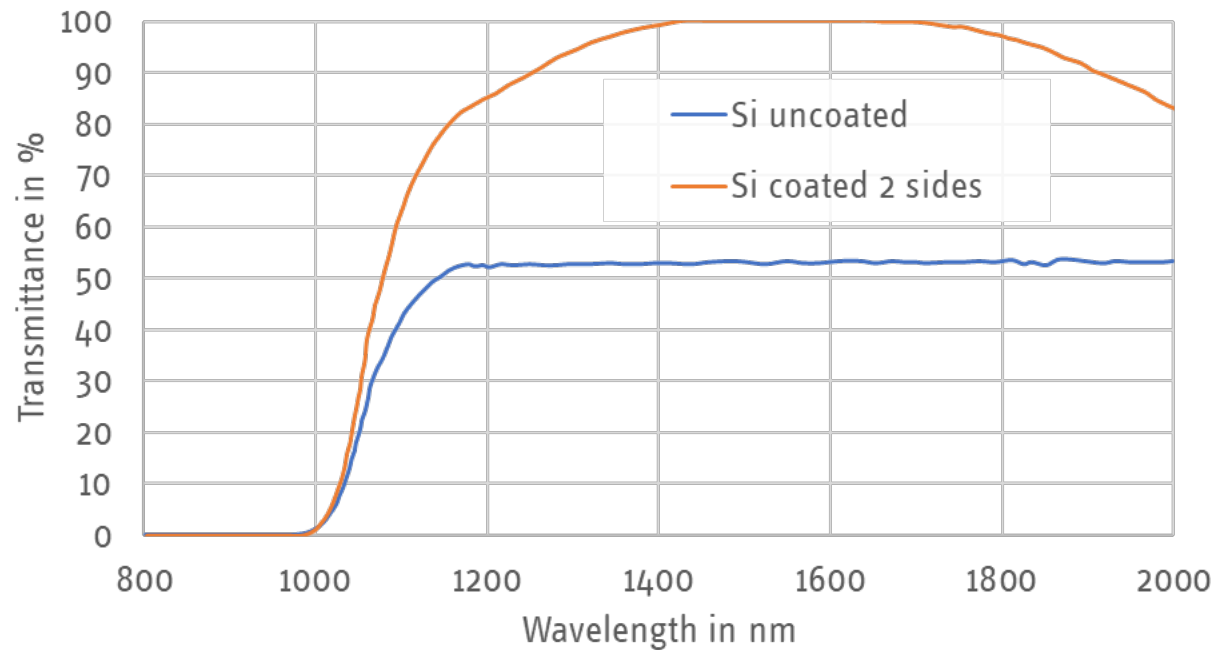
- Integration of laser source
- **Need for high-precision die bonding**

- Fiber array assembly and alignment
- Need for fiber interconnect

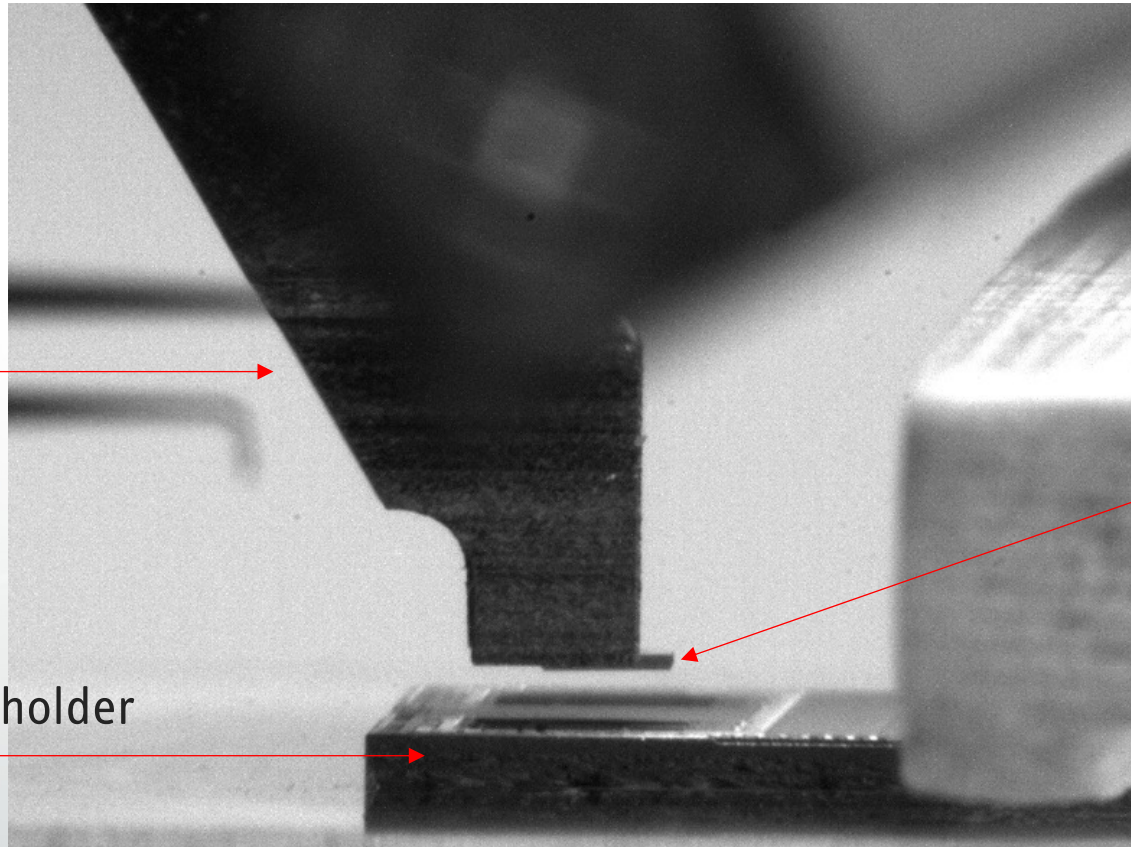
- Need for line systems and machine learning

High-precision die bonding

Transmittance over Wavelength of Silicon

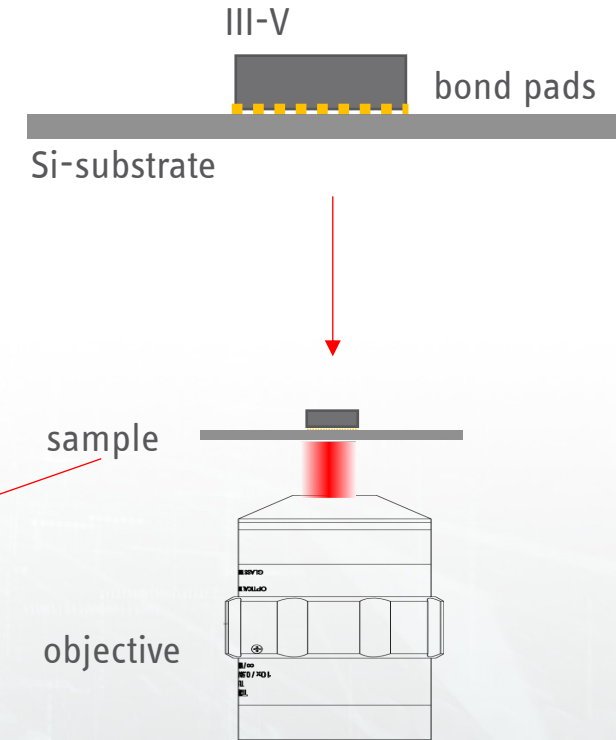


High-precision die bonding



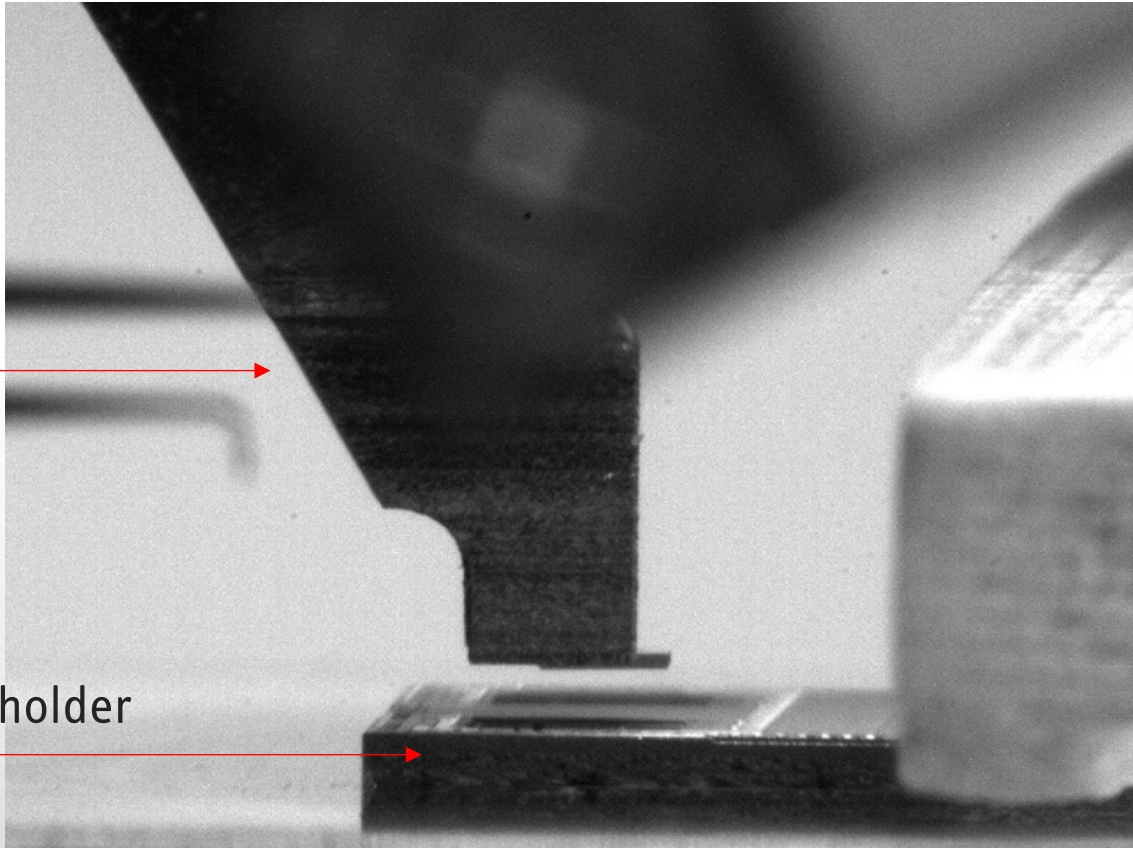
Pick-up tool on high-accuracy 6-axis aligner

SiP fixed on the holder



High-precision die bonding

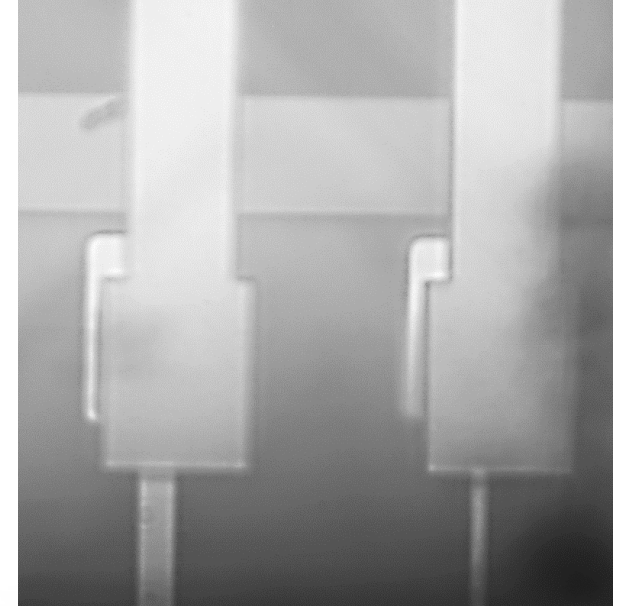
Pick-up tool on high-accuracy 6-axis aligner



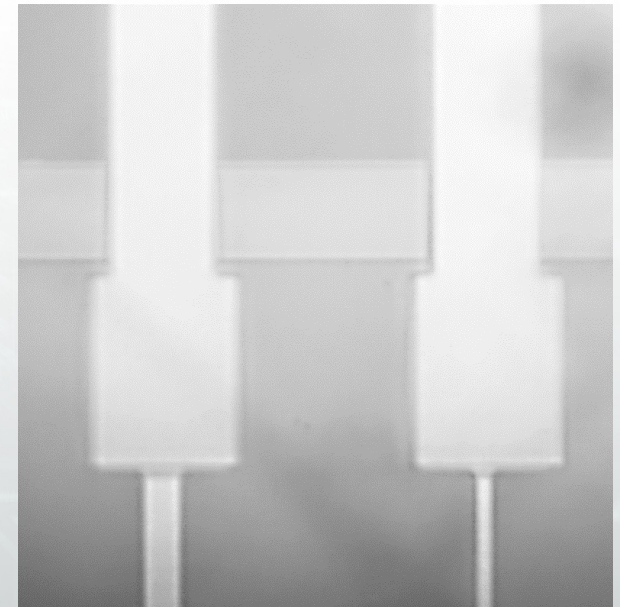
SiP fixed on the holder



Before alignment



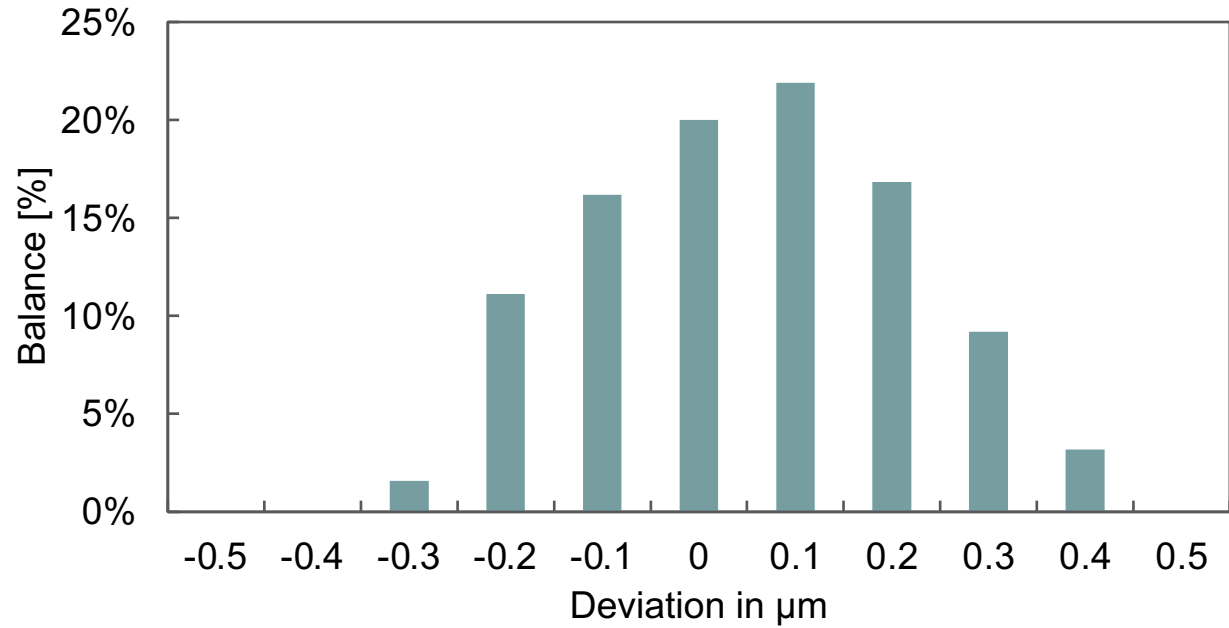
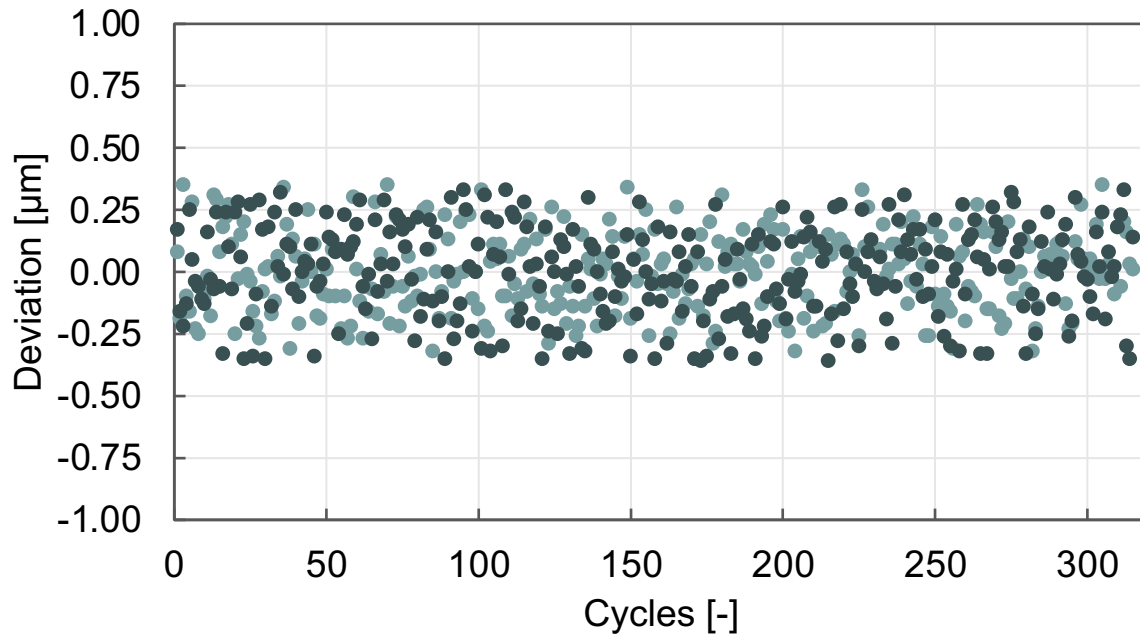
After alignment



ASSEMBLYLINE

Through-silicon Align-&-attach with IR

High-precision die bonding

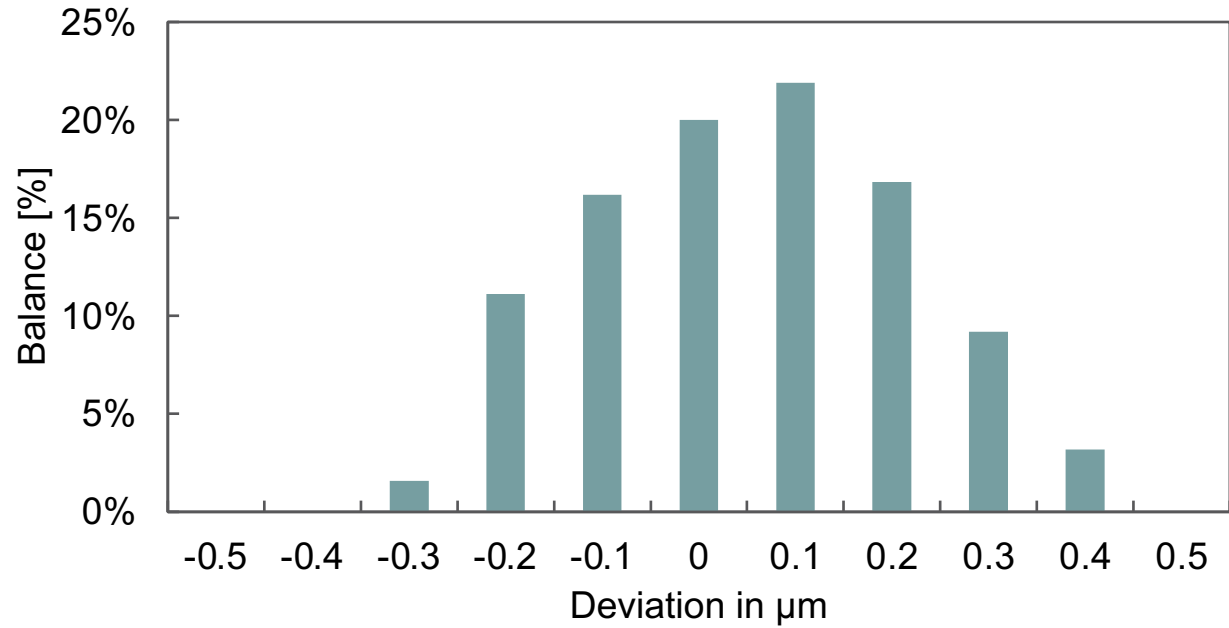
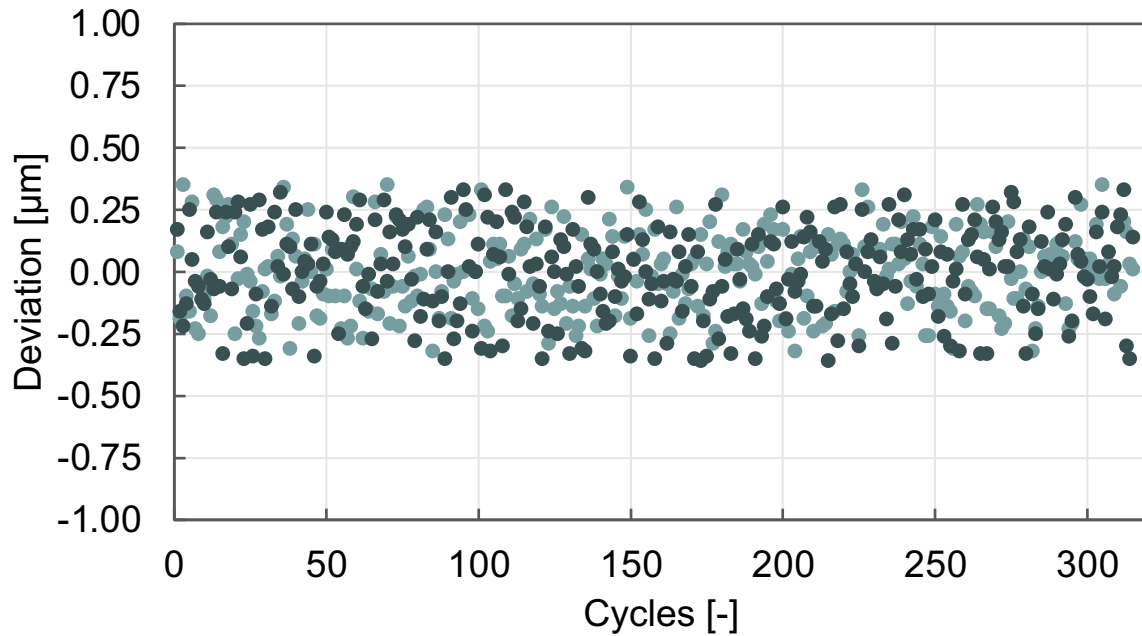


Alignment accuracy:

➤ In xy-direction → $3\sigma = \pm 0.22 \mu\text{m}$

Can be combined with localized through-silicon laser soldering

High-precision die bonding

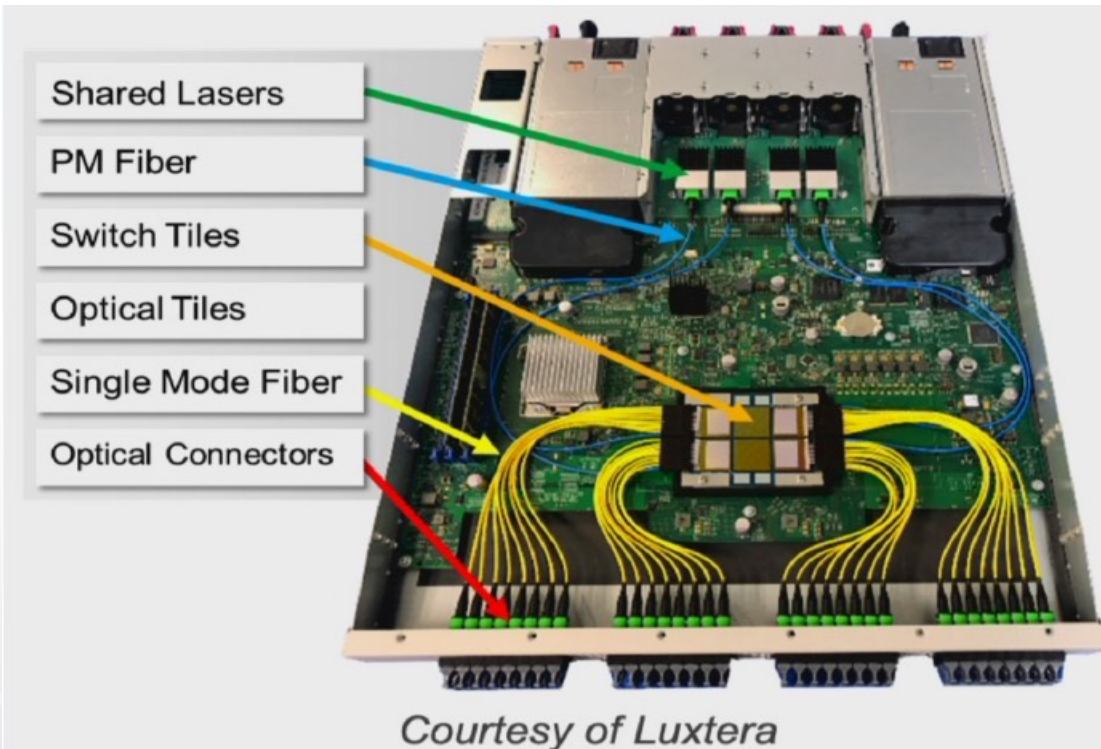


Alignment accuracy:

➤ In xy-direction → $3\sigma = +/- 0.22 \mu\text{m}$

**Wafer-level option available
 early this year !**

PIC product assembly



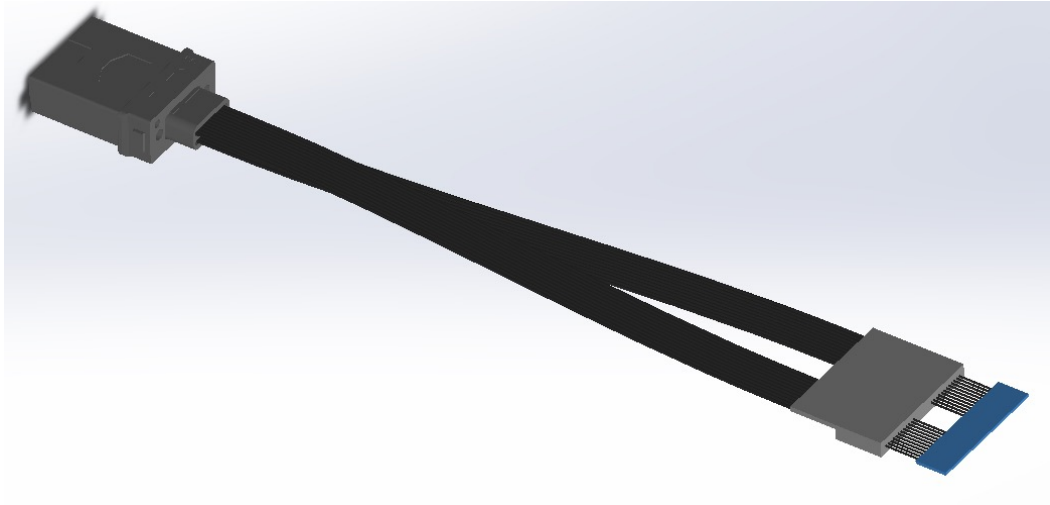
- Known good photonic integrated circuits (PICs)
- Need for electro-optical (wafer level) testing

- Integration of laser source
- Need for high-precision die bonding

- Fiber array assembly and alignment
- Need for fiber interconnect

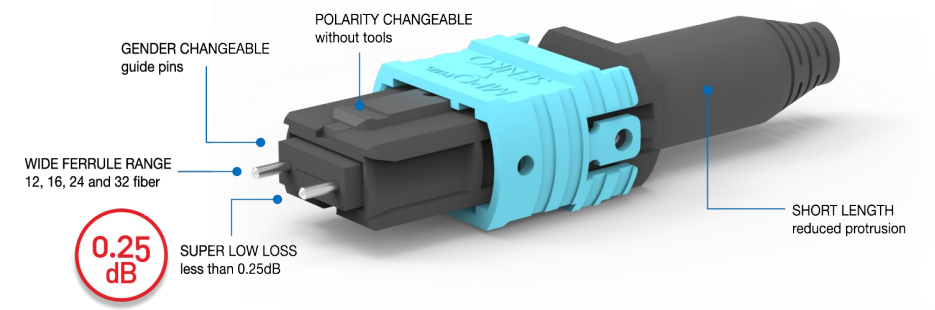
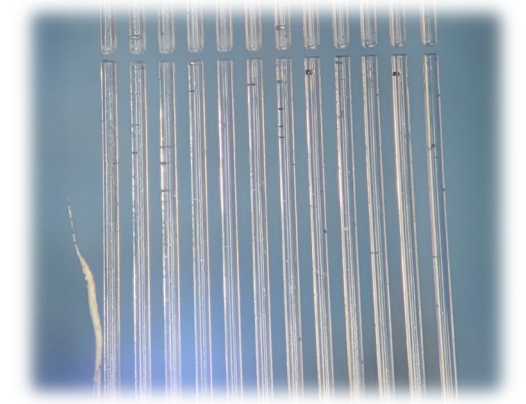
- Need for line systems and machine learning

Fiber interconnects



Fiber interconnect from chip to connector

Fiber preparation

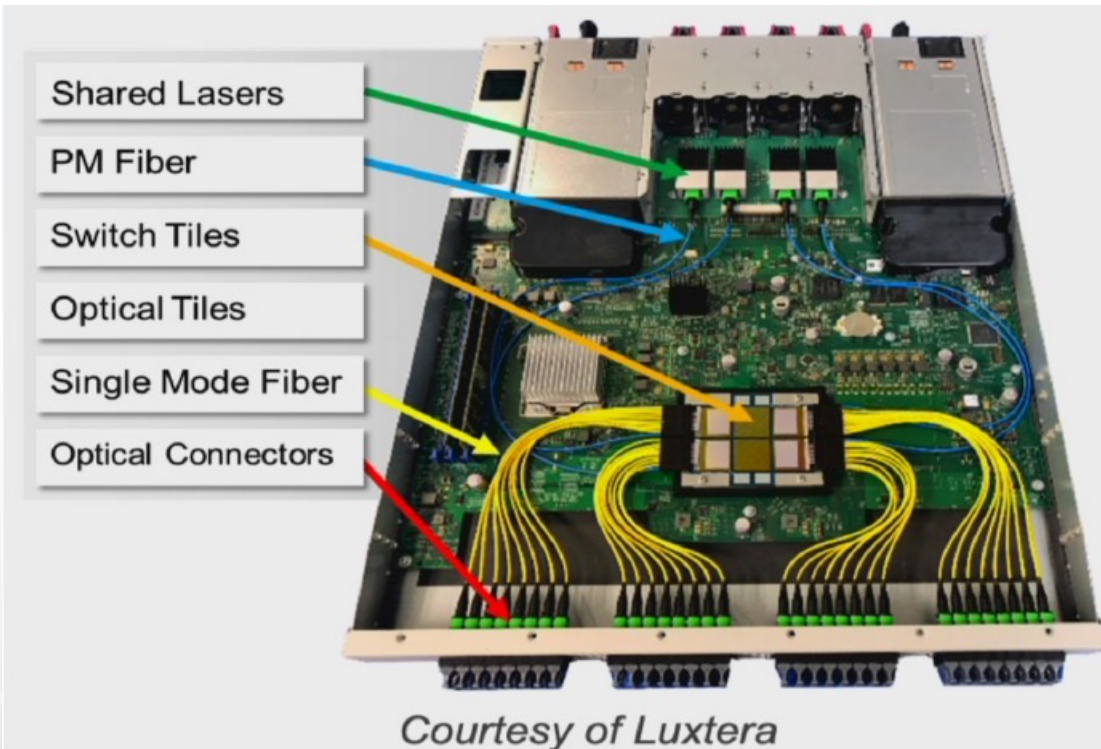


www.senko.com

Plug mounting

ficonteC
photonics assembly & testing

PIC product assembly



- Known good photonic integrated circuits (PICs)
- Need for electro-optical (wafer level) testing

- Integration of laser source
- Need for high-precision die bonding

- Fiber array assembly and alignment
- Need for fiber interconnect

- Reliable machine for volume production
- Need for line systems and machine learning

Line systems



Air purity optical detector sensor for a German Tier 1



Mass production site in Thailand with over 150 machines, incl. automatic module handling (cassette to cassette)

Machine learning

KPI tracking



AI/ML for process optimization



Assembly line

Required solutions



Wafer-level testing

+

High-precision
die bonding

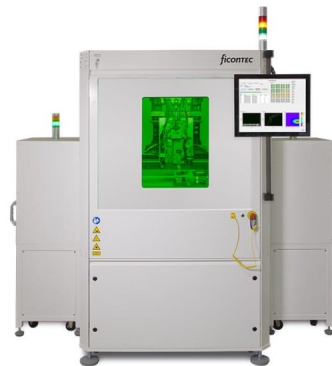
+



Fiber interconnects

+

Machine learning



Required solutions



Wafer-level testing

+

High-precision
die bonding

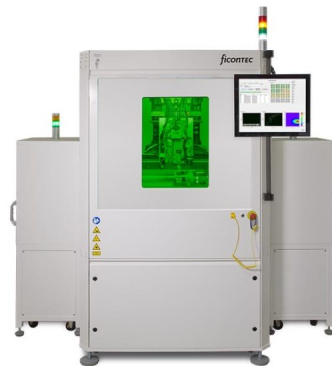
+



Fiber interconnects

+

Machine learning



Conclusions

- Assembly & Test are (and will remain) the cost driver for photonic products
- Automated assembly steps for most process steps available
- Last decade mainly focussed on improving individual assembly machine performance
- This decade will focus on increasingly higher levels of automation



Thank you!

Torsten Vahrenkamp
CEO

Im Finigen 3
28832 Achim, Germany

Torsten.Vahrenkamp@ficontec.com

+49-4202-51160400